

<p>FORM PTO-1449 (modified) To: U.S. Department of Commerce (PW FORM PAT-1449) Patent and Trademark Office</p> <p>INFORMATION DISCLOSURE STATEMENT BY APPLICANT</p>				Atty. Dkt. No.	Att'y Dkt. No.	Client Ref.				
					0304355	T1KK-01S1349-D				
				Applicant: MATSUDA et al.						
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				Filing Date: June 24, 2003						
Date: June 24, 2003		Page 1 of 1	Examiner: D. LE		Group Art Unit: 2818					
U.S. PATENT DOCUMENTS										
Examiner's Initials*	Document Number	Date MM/YYYY	Name (Family Name of First Inventor)		Class	Sub Class	Filing Date (if appropriate)			
AR	6,319,807	11/2001	Yeh et al.							
BR	6,353,249	03/2002	Boyd et al.							
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NR										
FOREIGN PATENT DOCUMENTS							English Abstract	Translation Readily Available		
	Document Number	Date MM/YYYY	Country	Inventor Name			Enclosed	No	Enclose	No
OR										
PR										
QR										
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VR	A. Chatterjee et al., "Sub-100nm Gate Length Metal Gate NMOS Transistors Fabricated by a Replacement Gate Process," IEDM, 1997, pp. 821-824									
WR	A. Chatterjee et al., "CMOS Metal Replacement Gate Transistors Using Tantalum Pentoxide Gate Insulator," IEDM, 1998, pp. 777-780									
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YR										
ZR										
AAR										
Examiner <i>John Doe</i>							Date Considered: <i>10/08/04</i>			
*EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP § 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to Applicant.										